Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/602,914	AMBE, CHITOSHI	
Examiner	Art Unit	_
VAN T. PHAM	2656	

	SEAR	CHED	
Class	Subclass	Date	Examiner
369	47.35	2/14/2006	VY
			<b>.</b>

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
PGPUB	text seath	2/14/2006	VY			
Interference search (see search history printout).						

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB)  369 (text search only see search history printout).	2/14/2006	VY		
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